| ATTY DOCKET NO. 35.C12395 CIP | APPLICATION NO. : CIP of 08/979,957 and 08/714,437 |
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| APPLICANT : YOSHIHIKO FUKUMOTO | |
| FILING DATE : Herewith | GROUP: Unassigned |

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Sheet 1 of 1

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| ATTY DOCKET NO. | APPLICATION NO. |
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| **35.C12395 CIP** | **09/429,530** |

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| **YOSHIHIKO FUKUMOTO** | | |
| FILING DATE **October 28, 1999** | GROUP **1765** | |

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Sheet 1 of 1

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PATENT AND TRADEMARK OFFICE

LIST OF REFERENCES CITED BY APPLICANT(S)
(Use several sheets if necessary)

| ATTY DOCKET NO. 35.C12395 CIP | APPLICATION NO. 09/429,530 |
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APPLICANT
**YOSHIHIKO FUKUMOTO**

| FILING DATE **October 28, 1999** | GROUP **1765** |
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